## INTEGRATED CIRCUITS



Product specification

1992 Nov 25

IC20 Data Handbook



### 80C851/83C851

#### DESCRIPTION

The Philips 80C851/83C851 is a high-performance microcontroller fabricated with Philips high-density CMOS technology. The 80C851/83C851 has the same instruction set as the 80C51. The Philips CMOS technology combines the high speed and density characteristics of HMOS with the low power attributes of CMOS. The Philips epitaxial substrate minimizes latch-up sensitivity.

The 80C851/83C851 contains a 4k  $\times$  8 ROM with mask-programmable ROM code protection, a 128  $\times$  8 RAM, 256  $\times$  8 EEPROM, 32 I/O lines, two 16-bit counter/timers, a seven-source, five vector, two-priority level nested interrupt structure, a serial I/O port for either multi-processor communications, I/O expansion or full duplex UART, and on-chip oscillator and clock circuits.

In addition, the 80C851/83C851 has two software selectable modes of power reduction — idle mode and power-down mode. The idle mode freezes the CPU while allowing the RAM, timers, serial port, and interrupt system to continue functioning. The power-down mode saves the RAM and EEPROM contents but freezes the oscillator, causing all other chip functions to be inoperative.

#### FEATURES

- 80C51 based architecture
  - 4k×8 ROM
  - 128×8 RAM
  - Two 16-bit counter/timers
  - Full duplex serial channel
  - Boolean processor
- Non-volatile 256 × 8-bit EEPROM (electrically erasable programmable read only memory)
  - On-chip voltage multiplier for erase/write
  - 50,000 erase/write cycles per byte
  - 10 years non-volatile data retention
  - Infinite number of read cycles
  - User selectable security mode
  - Block erase capability
- Mask-programmable ROM code protection
- Memory addressing capability
- 64k ROM and 64k RAMPower control modes:
- Idle mode
- Power-down mode
- CMOS and TTL compatible
- 1.2 to 16MHz
- Three package styles
- Three temperature ranges
- ROM code protection



#### **PIN CONFIGURATIONS**



## Product specification

### 80C851/83C851

#### **ORDERING INFORMATION**

PART ORDE	LIPS ER NUMBER ARKING	NORTH AMERICA PHILIPS PART ORDER NUMBER				
ROMIess Version	ROM Version	ROMIess Version	ROM Version	TEMPERATURE RANGE <sup>°</sup> C AND PACKAGE	FREQ. (MHz)	DRAWING NUMBER
P80C851 FBP	P83C851 FBP	S80C851-4N40	S83C851-4N40	0 to +70, Plastic Dual In-line Package	1.2 to 16	SOT129-1
P80C851 FBA	P83C851 FBA	S80C851-4A44	S83C851-4A44	0 to +70, Plastic Leaded Chip Carrier	1.2 to 16	SOT187-1
P80C851 FBB	P83C851 FBB	S80C851-4B44	S83C851-4B44	0 to +70, Plastic Quad Flat Pack	1.2 to 16	SOT307-2 <sup>1</sup>
P80C851 FFP	P83C851 FFP	S80C851-5N40	S83C851-5N40	-40 to +85, Plastic Dual In-line Package	1.2 to 16	SOT129-1
P80C851 FFA	P83C851 FFA	S80C851-5A44	S83C851-5A44	-40 to +85, Plastic Leaded Chip Carrier	1.2 to 16	SOT187-1
P80C851 FFB	P83C851 FFB	S80C851-5B44	S83C851-5B44	-40 to +85, Plastic Quad Flat Pack	1.2 to 16	SOT307-2 <sup>1</sup>
P80C851 FHP	P83C851 FHP	S80C851-6N40	S83C851-6N40	-40 to +125, Plastic Dual In-line Package	1.2 to 16	SOT129-1
P80C851 FHA	P83C851 FHA	S80C851-6A44	S83C851-6A44	-40 to +125, Plastic Leaded Chip Carrier	1.2 to 16	SOT187-1
P80C851 FHB	P83C851 FHB	S80C851-6B44	S83C851-6B44	-40 to +125, Plastic Quad Flat Pack	1.2 to 16	SOT307-2 <sup>1</sup>

NOTE:

1. SOT311 replaced by SOT307-2.

#### **BLOCK DIAGRAM**



## 80C851/83C851



#### **PIN FUNCTIONS** 44 34 P -0 1 💷 - 33 PQFP \_\_\_\_ 23 11 === 12 22 Pin Function Pin Function P1.5 P2.5/A13 1 23 2 P1.6 P2.6/A14 24 3 P1.7 25 P2.7/A15 4 RST 26 PSEN P3.0/RxD 27 ALE 5 NC\* 28 NC\* 6 P3.1/TxD FA 7 29 8 P3.2/INT0 30 P0.7/AD7 P3.3/INT1 9 31 P0.6/AD6 10 P3.4/T0 32 P0.5/AD5 11 P0.4/AD4 P3.5/T1 33 12 P3.6/WR 34 P0.3/AD3 13 P3.7RD 35 P0 2/AD2 14 XTAL2 36 P0.1/AD1 15 XTAL1 37 P0.0/AD0 16 V<sub>SS</sub> 38 V<sub>DD</sub> 17 NC\* 39 $\mathsf{V}_{\mathsf{SS}}$ 18 P2.0/A8 40 P1.0 19 41 P1.1 P2.1/A9 20 P2.2/A10 42 P1.2 21 P1.3 P2.3/A11 43 22 P2.4/A12 44 P1.4 DO NOT CONNECT

#### 1992 Nov 25

## 80C851/83C851

### **PIN DESCRIPTION**

	PIN NO.		PIN NO.		PIN NO.		PIN NO.		PIN NO.		
MNEMONIC	DIP	LCC	QFP	TYPE	NAME AND FUNCTION						
V <sub>SS</sub>	20	22	16, 39	I	Ground: 0V reference.						
V <sub>DD</sub>	40	44	38	I	<b>Power Supply:</b> This is the power supply voltage for normal, idle, and power-down operation.						
P0.0–0.7	39–32	43–36	37–30	I/O	<b>Port 0:</b> Port 0 is an open-drain, bidirectional I/O port. Port 0 pins that have 1s written to them float and can be used as high-impedance inputs. Port 0 is also the multiplexed low-order address and data bus during accesses to external program and data memory. In this application, it uses strong internal pull-ups when emitting 1s.						
P1.0-P1.7	1–8	2–9	40–44, 1–3	I/O	<b>Port 1:</b> Port 1 is an 8-bit bidirectional I/O port with internal pull-ups. Port 1 pins that have 1s written to them are pulled high by the internal pull-ups and can be used as inputs. As inputs, port 1 pins that are externally pulled low will source current because of the internal pull-ups. (See DC Electrical Characteristics: $I_{\rm IL}$ ).						
P2.0–P2.7	21–28	24–31	18–25	I/O	<b>Port 2:</b> Port 2 is an 8-bit bidirectional I/O port with internal pull-ups. Port 2 pins that have 1s written to them are pulled high by the internal pull-ups and can be used as inputs. As inputs, port 2 pins that are externally being pulled low will source current because of the internal pull-ups. (See DC Electrical Characteristics: I <sub>IL</sub> ). Port 2 emits the high-order address byte during fetches from external program memory and during accesses to external data memory that use 16-bit addresses (MOVX @DPTR). In this application, it uses strong internal pull-ups when emitting 1s. During accesses to external data memory that use 8-bit addresses (MOV @Ri), port 2 emits the contents of the P2 special function register.						
P3.0–P3.7	10–17	11, 13–19	5, 7–13	I/O	<b>Port 3:</b> Port 3 is an 8-bit bidirectional I/O port with internal pull-ups. Port 3 pins that have 1s written to them are pulled high by the internal pull-ups and can be used as inputs. As inputs, port 3 pins that are externally being pulled low will source current because of the pull-ups. (See DC Electrical Characteristics: $I_{IL}$ ). Port 3 also serves the special features of the SC80C51 family, as listed below:						
	10	11	5	1	RxD (P3.0): Serial input port						
	11	13	7	0	TxD (P3.1): Serial output port						
	12	14	8	1	INTO (P3.2): External interrupt						
	13	15	9		INT1 (P3.3): External interrupt						
	14	16	10		T0 (P3.4): Timer 0 external input						
	15	17	11		T1 (P3.5): Timer 1 external input						
	16 17	18 19	12 13	0	WR (P3.6): External data memory write strobe RD (P3.7): External data memory read strobe						
RST	9	10	4	I	<b>Reset:</b> A high on this pin for two machine cycles while the oscillator is running, resets the device. An internal diffused resistor to $V_{SS}$ permits a power-on reset using only an external capacitor to $V_{DD}$ .						
ALE	30	33	27	I/O	Address Latch Enable: Output pulse for latching the low byte of the address during an access to external memory. In normal operation, ALE is emitted at a constant rate of 1/6 the oscillator frequency, and can be used for external timing or clocking. Note that one ALE pulse is skipped during each access to external data memory.						
PSEN	29	32	26	0	<b>Program Store Enable:</b> The read strobe to external program memory. When the device is executing code from the external program memory, PSEN is activated twice each machine cycle, except that two PSEN activations are skipped during each access to external data memory. PSEN is not activated during fetches from internal program memory.						
ĒĀ	31	35	29	I	<b>External Access Enable:</b> If during a RESET, EA is held at TTL, level HIGH, the CPU executes out of the internal program memory ROM provided the Program Counter is less than 4096. If during a RESET, EA is held a TTL LOW level, the CPU executes out of external program memory. EA is not allowed to float.						
XTAL1	19	21	15	I	Crystal 1: Input to the inverting oscillator amplifier and input to the internal clock generator circuits.						
XTAL2	18	20	14	0	Crystal 2: Output from the inverting oscillator amplifier.						

### 80C851/83C851

SYMBOL	DESCRIPTION	DIRECT ADDRESS	BIT MSB		SS, SYME	BOL, OR A	LTERNAT	IVE PORT		ON LSB	RESET VALUE
ACC*	Accumulator	E0H	E7	E6	E5	E4	E3	E2	E1	E0	00H
B*	B register	F0H	F7	F6	F5	F4	F3	F2	F1	F0	00H
			EF	EE	ED	EC	EB	EA	E9	E8	
DPTR: DPH DPL	Data pointer (2 bytes): High byte Low byte	83H 82H									00H 00H
EADRH#	EEPROM addr reg-high	F3H									80H
EADRL#	EEPROM addr reg-low	F2H									00H
ECNTRL#	EEPROM control reg	F6H	IFE	EEINT	EWP	-	ECNTR L3	ECNTR L2	ECNTR L1	ECNTR L0	00H
EDAT#	EEPROM data register	F4H							•	•	ххН
ETIM#	EEPROM timer register	F5H									08H
			BF	BE	BD	BC	BB	BA	B9	B8	
IP*	Interrupt priority	B8H	-	-	-	PS	PT1	PX1	PT0	PX0	xxx00000B
			AF	AE	AD	AC	AB	AA	A9	A8	
IE*	Interrupt enable	A8H	EA	_	_	ES	ET1	EX1	ET0	EX0	0xx00000B
P0*	Port 0	80H	87	86	85	84	83	82	81	80	FFH
P1*	Port 1	90H	97	96	95	94	93	92	91	90	FFH
P2*	Port 2	A0H	A7	A6	A5	A4	A3	A2	A1	A0	FFH
P3*	Port 3	B0H	B7	B6	B5	B4	B3	B2	B1	B0	FFH
PCON	Power control	87H	SMOD	-	-	-	GF1	GF0	PD	IDL	0xxx0000B
			D7	D6	D5	D4	D3	D2	D1	D0	
PSW*	Program status word	D0H	CY	AC	F0	RS1	RS0	OV	-	Р	00H
SBUF	Serial data buffer	99H								-	хххххххВ
			9F	9E	9D	9C	9B	9A	99	98	
SCON*	Serial port control	98H	SM0	SM1	SM2	REN	TB8	RB8	ТІ	RI	00H
SP	Stack pointer	81H								-	07H
			8F	8E	8D	8C	8B	8A	89	88	00H
TCON*	Timer/counter con- trol	88H	TF1	TR1	TF0	TR0	IE1	IT1	IE0	ITO	00H
TMOD	Timer/counter mode	89H	GATE	C/T	M1	MO	GATE	C/T	M1	MO	00H
TH0	Timer 0 high byte	8CH									00H
TH1	Timer 1 high byte	8DH									00H
TL0	Timer 0 low byte	8AH									00H
TL1	Timer 1 low byte	8BH									00H

### Table 1. 8XC851 Special Function Registers

\* SFRs are bit addressable.

# SFRs are modified from or added to the 80C51 SFRs.

## 80C851/83C851

#### **EEPROM**

Communications between the CPU and the EEPROM is accomplished via 5 special function registers; 2 address registers (high and low byte), 1 data register for read and write operations, 1 control register, and 1 timer register to adapt the erase/write time to the clock frequency. All registers can be read and written. Figure 1 shows a block diagram of the CPU, the EEPROM and the interface.

with on-chip EEPROM

## Register and Functional Description

#### Address Register (EADRH, EADRL)

The lower byte contains the address of one of the 256 bytes. The higher byte (EADRH) is for future extensions and for addressing the security bits (see Security Facilities). The EADRH register address is F3H. The EADRL register address is F2H.

#### Data Register (EDAT)

This register is required for read and write operations and also for row/block erase. In write mode, its contents are written to the addressed byte (for "row erase" and "block erase" the contents are don't care). The write pulse starts all operations, except read. In read mode, EDAT contains the data of the addressed byte. The EDAT register address is F4H.

#### Timer Register (ETIM)

The timer register is required to adapt the erase/write time to the oscillator frequency. The user has to ensure that the erase or write (program) time is neither too short or too long. The ETIM register address is F5H. Table 2 contains the values which must be written to the ETIM register by software for various oscillator frequencies (the default value is 08H after RESET).

The general formula is:

2ms Write time:

Value (decimal,  
to be rounded up) 
$$= \frac{f_{XTAL1} [kHz]}{512} - 2$$

10ms Write time:

Value (decimal) = 
$$\frac{f_{XTAL1} [kHz]}{96} - 2$$

#### **Control Register (ECNTRL)**

See Figure 2 for a description of this register. The ECNTRL register address is F6H.

Table 2. Values for the Timer Register (ETIM)

CMOS single-chip 8-bit microcontroller

		VALUES F	OR ETIM		
f <sub>XTAL1</sub>	2ms WR	TE TIME	10ms WRITE TIME		
	HEX	DEC	HEX	DEC	
1.0MHz	-	-	08	8	
2.0MHz	02	2	13	19	
3.0MHz	04	4	1D	29	
4.0MHz	06	6	28	40	
5.0MHz	08	8	32	50	
6.0MHz	0A	10	3C	60	
7.0MHz	0C	12	47	71	
8.0MHz	0E	14	51	81	
9.0MHz	10	16	5C	92	
10.0MHz	12	18	66	102	
11.0MHz	14	20	71	113	
12.0MHz	16	22	7B	123	
13.0MHz	18	24			
14.0MHz	1A	26			
15.0MHz	1C	28			
16.0MHz	1E	30			



## 80C851/83C851

7	6	5	4	4	3	2	1	0
IFE	EEINT	EWF	P	- EC	NTRL3	ECNTRL2	ECNTRL1	ECNTRL0
Bit CNTRL. CNTRL. CNTRL. CNTRL. CNTRL. CNTRL.	<b>Symb</b> 7 IFE 6 EEINT 5 EWP 4 3-	ol Fu Active reset When serial EEPR Erase When reset Reset	unction high EEPF by software a set and en port interru ROM interru write in pro- EWP is se by software	ROM inter abled, this pt (see Int pt enable: ogress flag t, access	rupt flag s flag for terrupt s set and g: set an	set by the ces an inter ection). reset by so d reset by th	sequencer or rupt to the sa ftware (active he sequencer ot possible. E	l by software; me vector as high). (active high)
	Operatio	on E	CNTRL.3	ECNTR	L.2 E	CNTRL.1	ECNTRL.0	
R P bl	yte mode low erase lage write* lage erase/w lock erase Future produ		0 1 - 1	0 1 - 0		0 0 - 1	0 0  0	
yte mod	W	ritten to on	e byte at a t	time.			his mode, da This means t	
Write moo	de: T fi	his mode is rst. Since th	he old conte	by writing ents are re	to the da ad first (	ta register. by default),	The address this allows th I) is required.	e sequence
Row eras	i. o e	e. the 8 byt ne byte (t <sub>R(</sub> rase/write c	es addresse OWERASE = Cycle is requ	ed by EAE t <sub>E</sub> = t <sub>W</sub> ). F uired. For	ORL are For the fe example	cleared in the cllowing write , using the r	LSBs of EAD the same time the modes, onl the modes, onl the modes with the same time the same time time time time time time time ti	normally ne y the write a de, program
Page write	e: F	or future pr	oducts.					
Page eras	se/write: F	or future pr	oducts.					
Block era:							ining the sec nd EDAT are	
Program	Sequences	and Regis	ster Conter	nts after F	Reset			
The conte EADRH EADRL ETIM ECNTRL EDAT Initialize:	ents of the E = 1xxxxx = 00H = 08H = 00H = xxH MOV ET	xxxB (si (si (m (B (si fIM,	ecurity bit a ecurity bit a	ddress) ddress) ise time w			s: ssible oscillate	or frequency)
Read:	MOV EA MOV EA MOV,							
Write:	MOV EA MOV EA	ADRL,						
Erase row	MOV EC	CNTRL, #00	CH DAT) don't	Erase	ddress. row moo	3LSBs don' de	care	
Erase blo	ck: MOV EC MOV ED		H DAT) don't		block m	ode		
If the secu	urity bit is to	be altered,	the program	m general	ly starts	as follows:		
	DRH, #80H DRL, #00H							
			Figure 2.	Control	Registe	r (ECNTRL)	)	

#### Figure 2. Control Register (ECNTRL)

### 80C851/83C851

#### **Security Facilities**

#### **EEPROM Protection**

The EEPROM is protected using four security bits which are contained in an extra EEPROM byte at address 8000H (EADRH/EADRL). They can be set or cleared by software. To activate the EEPROM protection, the program sequence in byte mode must be as follows:

MOV	EADRH, #80H
MOV	EADRL, #00H
MOV	EDAT, #FFH

If two or more of these bits are reset, SB = 0, the security mode is disabled and the EEPROM is not protected. If three or four bits are set, SB = 1 and the  $\overline{EA}$  mode differs from the internal access mode.

In this case, access to the EEPROM is only possible in one mode regardless of how the external access mode is reached (by pulling the  $\overline{EA}$  pin low or by passing the 4K boundary). For SB = 1 and "external access" only, the "block erase" mode is enabled. The program sequence has to be as follows:

MOVEADRH, #80H (security byte address)MOVEADRL, #00H (security byte address)MOVECNTRL, #0AH (block erase mode)MOVEDAT, #xxH (start block erase)

All 256 data bytes, the security bits, and SB will be cleared after completing this mode (EWP = 0). SB will also be affected in byte mode when writing to the security byte (not for SB = 1 and "external access"). Figure 3 illustrates the access to SB.

#### **ROM Code Protection**

Since the external access mode can only be selected by pulling the  $\overline{EA}$  pin low during reset, it is not possible to read the internal program memory using the MOVC instruction while executing external program memory. Furthermore, it is not possible to change this

mode to internal access within the MOVC cycle.

Additionally, a mask-programmable ROM code protection facility is available. When the program memory passes the 4K boundary using both the internal and external ROMs, it is not possible to access the internal ROM from the external program memory if the mask-programmable ROM security bit is set. An access to the lower 4K bytes of program memory using the MOVC instruction is only possible while executing internal program memory.

Also the verification mode (test-mode which writes the ROM contents to a port for comparison with a reference code) is not implemented for security reasons. A different test-mode is implemented for test purposes. This mode allows every bit to be tested. However, the internal code cannot be accessed via a port.



### 80C851/83C851

### OSCILLATOR CHARACTERISTICS

XTAL1 and XTAL2 are the input and output, respectively, of an inverting amplifier. The pins can be configured for use as an on-chip oscillator, as shown in the logic symbol, page 2.

To drive the device from an external clock source, XTAL1 should be driven while XTAL2 is left unconnected. There are no requirements on the duty cycle of the external clock signal, because the input to the internal clock circuitry is through a divide-by-two flip-flop. However, minimum and maximum high and low times specified in the data sheet must be observed.

#### RESET

A reset is accomplished by holding the RST pin high for at least two machine cycles (24 oscillator periods), while the oscillator is running. To insure a good power-up reset, the RST pin must be high long enough to allow the oscillator time to start up (normally a few milliseconds) plus two machine cycles. At power-up, the voltage on V<sub>DD</sub> and RST must come up at the same time for a proper start-up.

**Note:** Before entering the idle or power-down modes, the user has to ensure that there is no EEPROM erase/write cycle in progress

(i.e., the EWP bit has to be reset before activating the idle or power-down modes; otherwise EEPROM accesses will be aborted).

#### **IDLE MODE**

In idle mode, the CPU puts itself to sleep while all of the on-chip peripherals stay active. The instruction to invoke the idle mode is the last instruction executed in the normal operating mode before the idle mode is activated. The CPU contents, the on-chip RAM, and all of the special function registers remain intact during this mode. The idle mode can be terminated either by any enabled interrupt (at which time the process is picked up at the interrupt service routine and continued), or by a hardware reset which starts the processor in the same manner as a power-on reset.

#### **POWER-DOWN MODE**

In the power-down mode, the oscillator is stopped and the instruction to invoke power-down is the last instruction executed. Only the contents of the on-chip RAM and EEPROM are preserved. A hardware reset is the only way to terminate the power-down mode. The control bits for the reduced power modes are in the special function register PCON. Table 3 shows the state of the I/O ports during low current operating modes.

#### **INTERRUPT SYSTEM**

External events and the real-time-driven on-chip peripherals require service by the CPU asynchronous to the execution of any particular section of code. To tie the asynchronous activities of these functions to normal program execution, a multiple-source, two-priority-level, nested interrupt system is provided. Interrupt response latency is from 3 $\mu$ s to 7 $\mu$ s when using a 12MHz crystal. The S83C851 acknowledges interrupt requests from 7 sources as follows:

- INTO and INT1: externally via pins 12 and 13, respectively,
- Timer 0 and timer 1: from the two internal counters,
- Serial port: from the internal serial I/O port or EEPROM (1 vector).

Each interrupt vectors to a separate location in program memory for its service program. Each source can be individually enabled (the EEPROM interrupt can only be enabled when the serial port interrupt is enabled) or disabled and can be programmed to a high or low priority level. All enabled sources can also be globally disabled or enabled. Both external interrupts can be programmed to be level-activated and are active low to allow "wire-ORing" of several interrupt sources to one input pin.

**Note:** The serial port and EEPROM interrupt flags must be cleared by software; all other flags are cleared by hardware.

#### Table 3. External Pin Status During Idle and Power-Down Modes

MODE	PROGRAM MEMORY	ALE	PSEN	PORT 0	PORT 1	PORT 2	PORT 3
Idle	Internal	1	1	Data	Data	Data	Data
Idle	External	1	1	Float	Data	Address	Data
Power-down	Internal	0	0	Data	Data	Data	Data
Power-down	External	0	0	Float	Data	Data	Data

#### ABSOLUTE MAXIMUM RATINGS<sup>1, 2, 3</sup>

PARAMETER	RATING	UNIT
Storage temperature range	-65 to +150	°C
Voltage on any other pin to $V_{SS}$	-0.5 to +6.5	V
Input or output DC current on any single I/O pin	±5	mA
Power dissipation (based on package heat transfer limitations, not device power consumption)	1.0	W

NOTES:

 Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any conditions other than those described in the AC and DC Electrical Characteristics section of this specification is not implied.

2. This product includes circuitry specifically designed for the protection of its internal devices from the damaging effects of excessive static charge. Nonetheless, it is suggested that conventional precautions be taken to avoid applying greater than the rated maxima.

3. Parameters are valid over operating temperature range unless otherwise specified. All voltages are with respect to V<sub>SS</sub> unless otherwise noted.

#### DC ELECTRICAL CHARACTERISTICS

 $T_{amb} = 0^{\circ}C \text{ to } +70^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), -40^{\circ}C \text{ to } +85^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), \text{ or } -40^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 5V \pm 10\%), V_{SS} = 0V \pm 10^{\circ}C \text{ to } +125^{\circ}C \text{ (V}_{DD} = 10^{\circ}C \text{ to } +10^{\circ}C \text{ to } +10^{\circ}C \text{ to } +10^{\circ}C \text{ to$ 

		PART	TEST	LIM	IITS	
SYMBOL	PARAMETER	TYPE	CONDITIONS	MIN	MAX	UNIT
V <sub>IL</sub>	Input low voltage, except EA	0 to +70°C -40 to +85°C -40 to +125°C		-0.5 -0.5 -0.5	0.2V <sub>DD</sub> -0.1 0.2V <sub>DD</sub> -0.15 0.2V <sub>DD</sub> -0.25	V V V
V <sub>IL1</sub>	Input low voltage to EA	0 to +70°C -40 to +85°C -40 to +125°C		-0.5 -0.5 -0.5	0.2V <sub>DD</sub> -0.3 0.2V <sub>DD</sub> -0.35 0.2V <sub>DD</sub> -0.45	V V V
VIH	Input high voltage, except XTAL1, RST	0 to +70°C -40 to +85°C -40 to +125°C		0.2V <sub>DD</sub> +0.9 0.2V <sub>DD</sub> +1.0 0.2V <sub>DD</sub> +1.0	V <sub>DD</sub> +0.5 V <sub>DD</sub> +0.5 V <sub>DD</sub> +0.5	V V V
V <sub>IH1</sub>	Input high voltage, XTAL1, RST	0 to +70°C -40 to +85°C -40 to +125°C		0.7V <sub>DD</sub> 0.7V <sub>DD</sub> +0.1 0.7V <sub>D</sub> +0.1	V <sub>DD</sub> +0.5 V <sub>DD</sub> +0.5 V <sub>DD</sub> +0.5	
V <sub>OL</sub>	Output low voltage, ports 1, 2, 3 <sup>6</sup>		$I_{OL} = 1.6 \text{mA}^4$		0.45	V
V <sub>OL1</sub>	Output low voltage, port 0, ALE, PSEN 6		$I_{OL} = 3.2 \text{mA}^4$		0.45	V
V <sub>OH</sub>	Output high voltage, ports 1, 2, 3, ALE, PSEN		I <sub>OH</sub> = –60μΑ, I <sub>OH</sub> = –25μΑ, I <sub>OH</sub> = –10μΑ	2.4 0.75V <sub>DD</sub> 0.9V <sub>DD</sub>		V V V
V <sub>OH1</sub>	Output high voltage, port 0 in external bus mode <sup>5</sup>		I <sub>OH</sub> = -800μA, I <sub>OH</sub> = -300μA, I <sub>OH</sub> = -80μA	2.4 0.75V <sub>DD</sub> 0.9V <sub>DD</sub>		V V V
IIL	Logical 0 input current, ports 1, 2, 3	0 to +70°C -40 to +85°C -40 to +125°C	V <sub>IN</sub> = 0.45V		-50 -75 -75	μΑ μΑ μΑ
I <sub>TL</sub>	Logical 1-to-0 transition current, ports 1, 2, 3	0 to +70°C -40 to +85°C -40 to +125°C	V <sub>IN</sub> = 2.0V		650 750 750	μΑ μΑ μΑ
I <sub>L1</sub>	Input leakage current, port 0, EA		0.45V <v<sub>i<v<sub>DD</v<sub></v<sub>		±10	μΑ
I <sub>DD</sub>	Power supply current: Active mode @ 16MHz <sup>1</sup> Idle mode @ 16MHz <sup>2</sup> Power down mode <sup>3</sup>		See note 7		19 3.7 50	mA mA μA
R <sub>RST</sub>	Internal reset pull-down resistor			50	150	kΩ
C <sub>IO</sub>	Pin capacitance		f = 1MHz		10	рF

NOTES:

The operating supply current is measured with all output pins disconnected; XTAL1 driven with  $t_r = t_f = 5ns$ ;  $V_{1L} = V_{SS} + 0.5V$ ; 1.  $V_{IH} = V_{DD} - 0.5V$ ; XTAL2 not connected;  $\overline{EA} = RST = Port 0 = V_{DD}$ .

2. The idle mode supply current is measured with all output pins disconnected; XTAL1 driven with  $t_r = t_f = 5ns$ ;  $V_{IL} = V_{SS} + 0.5V$ ;

 $V_{IH} = V_{DD} - 0.5V$ ; XTAL2 not connected;  $\overline{EA} = Port 0 = V_{DD}$ ; RST =  $V_{SS}$ . 3. The power-down current is measured with all output pins disconnected; XTAL2 not connected;  $\overline{EA} = Port 0 = V_{DD}$ ; RST = XTAL1 =  $V_{SS}$ . Capacitive loading on Port 0 and Port 2 may cause spurious noise pulses to be superimposed on the LOW level output voltage of ALE, Port 4. 1 and Port 3. The noise is due to external bus capacitance discharging into the Port 0 and Port 2 pins when these pins make a 1-to-0 transition during bus operations. In the worst cases (capacitive loading > 100pF), the noise pulse on the ALE line may exceed 0.8V. In such cases it may be desirable to qualify ALE with a Schmitt Trigger, or use an address latch with a Schmitt Trigger STROBE input.

Capacitive loading on Port 0 and Port 2 may cause the HIGH level output voltage on ALE and PSEN to momentarily fall below the 0.9VDD 5. specification when the address bits are stabilizing.

6. Under steady state (non-transient) conditions, IOL must be externally limited as follows:

10mA

Maximum IOL per Port pin:

Maximum IOL per 8-bit port -

Port 0:	26mA
orts 1, 2, and 3:	15mA
	74

Maximum total I<sub>OL</sub> for all output pins: 71mA.

If IOL exceeds the test condition, VOL may exceed the related specification. Pins are not guaranteed to sink current greater than the listed test conditions.

7. See Figures 11 through 14 for I<sub>DD</sub> test conditions.

Product specification

### 80C851/83C851

### **AC ELECTRICAL CHARACTERISTICS**<sup>1, 2</sup>

			16MHz	CLOCK	VARIABL	E CLOCK	
SYMBOL	FIGURE	PARAMETER	MIN	MAX	MIN	MAX	דואט
/t <sub>CLCL</sub>	4	Oscillator frequency			1.2	16	MHz
LHLL	4	ALE pulse width	85		2t <sub>CLCL</sub> -40		ns
AVLL	4	Address valid to ALE low	8		t <sub>CLCL</sub> –55		ns
LLAX	4	Address hold after ALE low	28		t <sub>CLCL</sub> -35		ns
LLIV	4	ALE low to valid instruction in		150		4t <sub>CLCL</sub> -100	ns
LLPL	4	ALE low to PSEN low	23		t <sub>CLCL</sub> -40		ns
PLPH	4	PSEN pulse width	143		3t <sub>CLCL</sub> -45		ns
PLIV	4	PSEN low to valid instruction in		83		3t <sub>CLCL</sub> -105	ns
PXIX	4	Input instruction hold after PSEN	0		0		ns
PXIZ	4	Input instruction float after PSEN		38		t <sub>CLCL</sub> -25	ns
AVIV	4	Address to valid instruction in		208		5t <sub>CLCL</sub> -105	ns
t <sub>PLAZ</sub>	4	PSEN low to address float		10		10	ns
Data Memo	ry		I		1		
t <sub>RLRH</sub>	5, 6	RD pulse width	275		6t <sub>CLCL</sub> -100		ns
twlwh	5, 6	WR pulse width	275		6t <sub>CLCL</sub> -100		ns
RLDV	5, 6	RD low to valid data in		148		5t <sub>CLCL</sub> -165	ns
RHDX	5, 6	Data hold after RD	0		0		ns
RHDZ	5, 6	Data float after RD		55		2t <sub>CLCL</sub> -70	ns
	5, 6	ALE low to valid data in		350		8t <sub>CLCL</sub> -150	ns
t <sub>AVDV</sub>	5, 6	Address to valid data in		398		9t <sub>CLCL</sub> -165	ns
t <sub>LLWL</sub>	5, 6	ALE low to RD or WR low	138	238	3t <sub>CLCL</sub> -50	3t <sub>CLCL</sub> +50	ns
t <sub>AW</sub>	5, 6	Address to RD or WR	120		4t <sub>CLCL</sub> -130	0101	ns
t <sub>QW</sub>	5, 6	Data setup time before WR	288		7t <sub>CLCL</sub> -150		ns
t <sub>QVWX</sub>	5, 6	Data valid to WR transition	3		t <sub>CLCL</sub> -60		ns
twhox	5, 6	Data hold after WR	13		t <sub>CLCL</sub> -50		ns
	5, 6	RD low to address float		0		0	ns
twhlh	5, 6	RD or WR high to ALE high	23	103	t <sub>CLCL</sub> -40	t <sub>CLCL</sub> +40	ns
External Cl		· · ·			0101	0101	
tснсх	8	High time	20		20		ns
tCLCX	8	Low time	20		20		ns
t <sub>CLCH</sub>	8	Rise time		20		20	ns
	8	Fall time		20		20	ns
	timer const			1			
<sup>t</sup> E/W		Erase/write cycle time	4	20	4	20	ms
E		Erase time	2	10	2	10	ms
t <sub>W</sub>		Write time	2	10	2	10	ms
t <sub>S</sub>		Data retention time <sup>4</sup>	10		10		year
NE/W		Erase/write cycles <sup>5</sup>	50,000		50,000		cycle

NOTES:

Parameters are valid over operating temperature range unless otherwise specified.
 Load capacitance for port 0, ALE, and PSEN = 100pF, load capacitance for all other outputs = 80pF.

 The power-off fall-time of V<sub>DD</sub> must be less than 1ms to prevent an overwrite pulse from being generated in the EEPROM which can cause spurious parasitic writing to EEPROM cells. If the V<sub>DD</sub> power-off full-time is greater than 1ms, a power-off reset signal should be generated to prevent this condition from occurring. 4. Test condition:  $T_{amb} = +55^{\circ}C$ . 5. Number of erase/write cycles for each EEPROM byte.

### 80C851/83C851

#### **EXPLANATION OF THE AC SYMBOLS**

Each timing symbol has five characters. The first character is always 't' (= time). The other characters, depending on their positions, indicate the name of a signal or the logical status of that signal. The designations are: A - Address

- C Clock
- D Input data
- H Logic level high
- I Instruction (program memory contents)

L - Logic level low, or ALE

- P PSEN
- Q Output data
- R RD signal
- t Time V Valid
- W- WR signal
- X No longer a valid logic level
- Z Float

#### Examples: t<sub>AVLL</sub>= Time for address valid to

ALE low.

t<sub>LLPL</sub>= Time for ALE low to





Figure 4. External Program Memory Read Cycle



## 80C851/83C851





## 80C851/83C851

#### Table 4. External Clock Drive XTAL1

Oscillator circuitry: The capacities connected to the crystal should be: C1 = C2 = tbf.

		VARIABL f = 1.2 -		
SYMBOL	PARAMETER	MIN	MAX	UNIT
t <sub>CLCL</sub>	Oscillator clock period	63	833	ns
t <sub>HIGH</sub>	HIGH time	20	$t_{CLCL} - t_{LOW}$	ns
t <sub>LOW</sub>	LOW time	20	t <sub>CLCL</sub> – t <sub>HIGH</sub>	ns
t <sub>r</sub>	Rise time	-	20	ns
t <sub>f</sub>	Fall time	-	20	ns
t <sub>CY</sub>	Cycle time <sup>1</sup>	0.75	10	ns

NOTE:

1.  $t_{CY} = 12 t_{CLCL}$ .



NOTE:

For timing purposes, a port is no longer floating when a 100mV change from load voltage occurs, and begins to float when a 100mV change from the loaded V<sub>OH</sub>/V<sub>OL</sub> level occurs. I<sub>OH</sub>/I<sub>OL</sub>  $\geq \pm$  20mA.

Figure 10. Float Waveform

## 80C851/83C851



## 80C851/83C851



UNIT	A max.	A <sub>1</sub> min.	A <sub>2</sub> max.	b	b <sub>1</sub>	c	р <sup>(1)</sup>	E <sup>(1)</sup>	е	e <sub>1</sub>	L	M <sub>E</sub>	M <sub>H</sub>	w	Z <sup>(1)</sup> max.
mm	4.7	0.51	4.0	1.70 1.14	0.53 0.38	0.36 0.23	52.50 51.50	14.1 13.7	2.54	15.24	3.60 3.05	15.80 15.24	17.42 15.90	0.254	2.25
inches	0.19	0.020	0.16	0.067 0.045	0.021 0.015	0.014 0.009	2.067 2.028	0.56 0.54	0.10	0.60	0.14 0.12	0.62 0.60	0.69 0.63	0.01	0.089

#### Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	EIAJ		PROJECTION	1550E DATE	
SOT129-1	051G08	MO-015AJ				<del>-92-11-17</del> 95-01-14	

80C851/83C851



#### DIMENSIONS (millimetre dimensions are derived from the original inch dimensions)

UNIT	А	A <sub>1</sub> min.	Α3	A <sub>4</sub> max.	bp	b <sub>1</sub>	D <sup>(1)</sup>	E <sup>(1)</sup>	е	е <sub>D</sub>	еE	H <sub>D</sub>	Η <sub>E</sub>	k	k <sub>1</sub> max.	Lp	v	w	у	Z <sub>D</sub> <sup>(1)</sup> max.	Z <sub>E</sub> <sup>(1)</sup> max.	β
mm	4.57 4.19	0.51	0.25	3.05	0.53 0.33	0.81 0.66	16.66 16.51		1.27		16.00 14.99			1.22 1.07	0.51	1.44 1.02	0.18	0.18	0.10	2.16	2.16	45 <sup>0</sup>
inches	0.180 0.165	0.020	0.01				0.656 0.650		0.05	0.630 0.590	0.630 0.590	0.695 0.685	0.695 0.685	0.048 0.042	0.020	0.057 0.040	0.007	0.007	0.004	0.085	0.085	45

#### Note

1. Plastic or metal protrusions of 0.01 inches maximum per side are not included.

OUTLINE		REFER	REFERENCES EUROPEAN							
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE				
SOT187-2	112E10	MO-047AC				<del>92-11-17</del> 95-02-25				

Product specification

80C851/83C851



### 80C851/83C851

DEFINITIONS							
Data Sheet Identification	Product Status	Definition					
Objective Specification	Formative or in Design	This data sheet contains the design target or goal specifications for product development. Specifications may change in any manner without notice.					
Preliminary Specification	Preproduction Product	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.					
Product Specification	Full Production	This data sheet contains Final Specifications. Philips Semiconductors reserves the right to make changes at any time without notice, in order to improve design and supply the best possible product.					

Philips Semiconductors and Philips Electronics North America Corporation reserve the right to make changes, without notice, in the products, including circuits, standard cells, and/or software, described or contained herein in order to improve design and/or performance. Philips Semiconductors assumes no responsibility or liability for the use of any of these products, conveys no license or title under any patent, copyright, or mask work right to these products, and makes no representations or warranties that these products are free from patent, copyright, or mask work right infringement, unless otherwise specified. Applications that are described herein for any of these products are for illustrative purposes only. Philips Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

#### LIFE SUPPORT APPLICATIONS

Philips Semiconductors and Philips Electronics North America Corporation Products are not designed for use in life support appliances, devices, or systems where malfunction of a Philips Semiconductors and Philips Electronics North America Corporation Product can reasonably be expected to result in a personal injury. Philips Semiconductors and Philips Electronics North America Corporation customers using or selling Philips Semiconductors and Philips Electronics North America Corporation so at their own risk and agree to fully indemnify Philips Semiconductors and Philips Electronics North America Corporation for any damages resulting from such improper use or sale.

Philips Semiconductors 811 East Arques Avenue P.O. Box 3409 Sunnyvale, California 94088–3409 Telephone 800-234-7381 © Copyright Philips Electronics North America Corporation 1997 All rights reserved. Printed in U.S.A.

Let's make things better.



